

## Notice of References Cited

Application/Control No. 09/763,578	Reexaminatio	Applicant(s)/Patent Under Reexamination EDEN, RUTH F.		
Examiner	Art Unit			
Bao-Thuy L. Nguyen	1641	Page 1 of 1		

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,230,685	10-1980	Senyei et al	
	В	US-4,677,055	06-1987	Dodin et al	
	С	US-4,695,393	09-1987	Whitehead et al	
	D	US-5,081,035	01-1992	Halberstadt et al	
	ε	US-5,409,822	04-1995	Scott et al	
	F	US-5,491,068	02-1996	Benjamin et al	
	G	US-5,567,615	10-1996	Degen et al	·
	Н	US-5,695,946	12-1997	Benjamin et al	
	-	US-5,866,006	02-1999	Lihme et al	
	٦	US-6,395,537	05-200 \$ 2	Eden et al	
	κ	US-			
٠	L	US-	·		
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	95/21241	08-1995	wo	Difco Laboratories	
	0					
	Ρ					
	Q			·		
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	υ				
	v				
	w				
	х				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

U.S. Patent and Trademark Office PTO-892 (Rev. 01-2001)

**Notice of References Cited** 

Part of Paper No. 5